

AMENDMENTS TO THE ABSTRACT:

This listing of abstract will replace all prior versions, and listings, of abstracts in the application:

Listing of the Abstract:

Please replace the abstract on page 44 with the following:

The invention proposes a method and a measuring system for testing the function of LCD displays comprising individual display segments, based on the difference in the electrical capacitance C_{seg} of defective and intact display segments. The method is based on the direct determination of the capacitance of the display segments with a capacitance measuring method by measuring the stored electrical charge. As a preferred measuring method, a method is proposed, in which a charge transfer through a reference capacitor C_{ref} proceeds and the segment capacitance C_{seg} is determined by means of a charge balance, preferably by means of a $\Delta\Sigma$ conversion.

(Fig. 4)